

Application No.	Applicant(s)	
10/005,338	DENEFLE ET AL.	
Examiner	Art Unit	
Dave T. Nouven	1632	

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SEARCHED					
Class	Subclass	Date	Examiner		
same as	indicated previously	12/9/2004	DTN		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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sequence searched by STIC-CHem. searched notes reviewed.	DATE	EXMR DTN
sequence searched by STIC-CHem. searched notes reviewed.	12/9/2004	DTN
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